



N 沟道增强型场效应晶体管  
N-CHANNEL MOSFET  
FHP150N04A

主要参数 MAIN CHARACTERISTICS

ID	150 A
VDSS	40 V
Rdson-typ (@Vgs=10V)	2.1 mΩ
Qg-typ	79.1 nC

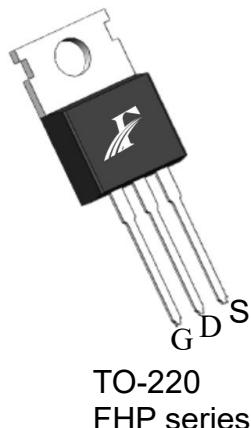
用途 APPLICATIONS

开关电源	Switch Mode Power Supplies
DC-DC转换器	DC-DC converter
逆变电源	Power management for inverter systems

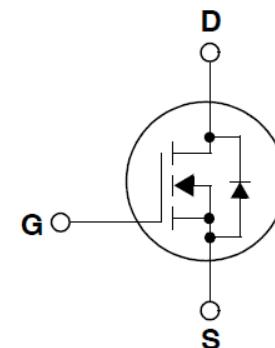
产品特性 FEATURES

低栅极电荷	Low gate charge
低 Crss (典型值 637 pF)	Low Crss (typical 637 pF)
开关速度快	Fast switching
100% 经过 Rg 测试	100% Rg tested
100% 经过雪崩测试	100% avalanche tested
100% 经过热阻测试	100% DVDS tested
符合 RoHS 标准	ROHS compliant

封装形式 Package



等效电路 Equivalent Circuit



绝对最大额定值 ABSOLUTE RATINGS (Tc=25°C)

项目 Parameter	符号 Symbol	数值 Value	单位 Unit
		FHP150N04A	
最高漏极—源极直流电压 Drain-Source Voltage	VDS	40	V
连续漏极电流* Drain Current -continuous *	Id (Tc=25°C)	150	A
	Id (Tc=100°C)	96	A
最大脉冲漏极电流 (注 1) Drain Current – pulse (note 1)	IdM	600	A
最高栅源电压 Gate-Source Voltage	Vgs	±20	V
单脉冲雪崩能量 (注 2) Single Pulsed Avalanche Energy (note 2)	EAS	220.5	mJ
雪崩电流 (注 1) Avalanche Current (note 1)	IAR	21	A
二极管反向恢复最大电压变化速率 (注 3) Peak Diode Recovery dv/dt (note 3)	dv/dt	5.0	V/ns
耗散功率 Power Dissipation	PD (TC=25°C)	178.5	W
	-Derate above 25°C	1.4	W/°C
最高结温及存储温度 Operating and Storage Temperature Range	TJ, TSTG	150, -55~+150	°C
引线最高焊接温度 Maximum Lead Temperature for Soldering Purposes	TL	300	°C

\*漏极电流由最高结温限制

\*Drain current limited by maximum junction temperature

## 电特性 ELECTRICAL CHARACTERISTICS

项目 <b>Parameter</b>	符号 <b>Symbol</b>	测试条件 <b>Tests conditions</b>	最小 <b>Min</b>	典型 <b>Typ</b>	最大 <b>Max</b>	单位 <b>Units</b>	
<b>关态特性 Off -Characteristics</b>							
漏一源击穿电压 Drain-Source Voltage	BVDSS	ID=250μA, VGS=0V	40	-	-	V	
击穿电压温度特性 Breakdown Voltage Temperature Coefficient	ΔBVDSS/Δ TJ	ID=250μA, referenced to 25°C	-	0.04	-	V/°C	
零栅压下漏极漏电流 Zero Gate Voltage Drain Current	IDSS	VDS=40V, VGS=0V, TC=25°C	-	-	1	μA	
		VDS=32V, TC=125°C	-	-	100	μA	
栅极体漏电流 Gate-body leakage current	IGSS (F/R)	VDS=0V, VGS =±20V	-	-	±100	nA	
<b>通态特性 On-Characteristics</b>							
阈值电压 Gate Threshold Voltage	VGS(th)	VDS = VGS , ID=250μA	2.0	-	4.0	V	
静态导通电阻 Static Drain-Source On-Resistance	RDS(ON)	VGS =10V , ID=50A	-	2.1	3.0	mΩ	
<b>动态特性 Dynamic Characteristics</b>							
栅电阻 Gate Resistance	Rg	f=1.0MHz, VDS OPEN	-	3.6	-	Ω	
输入电容 Input capacitance	Ciss	VDS=20V, VGS =0V, f=1.0MHz	-	7047	-	pF	
输出电容 Output capacitance	Coss		-	670	-		
反向传输电容 Reverse transfer capacitance	Crss		-	637	-		
<b>开关特性 Switching Characteristics</b>							
延迟时间 Turn-On delay time	td(on)	VDD=20V, ID=50A, RG=6Ω VGS =10V (note 4, 5)	-	14.8	-	ns	
上升时间 Turn-On rise time	tr		-	15.2	-	ns	
延迟时间 Turn-Off delay time	td(off)		-	119.6	-	ns	
下降时间 Turn-Off Fall time	tf		-	59.2	-	ns	
栅极电荷总量 Total Gate Charge	Qg	VDS =20V , ID=50A , VGS =10V (note 4, 5)	-	79.1	-	nC	
栅一源电荷 Gate-Source charge	Qgs		-	13.6	-	nC	
栅一漏电荷 Gate-Drain charge	Qgd		-	16.5	-	nC	
<b>漏一源二极管特性及最大额定值 Drain-Source Diode Characteristics and Maximum Ratings</b>							
正向最大连续电流 Maximum Continuous Drain-Source Diode Forward Current	Is		-	-	150	A	
正向最大脉冲电流 Maximum Pulsed Drain-Source Diode Forward Current	ISM		-	-	600	A	
正向压降 Drain-Source Diode Forward Voltage	VSD	VGS=0V, Is=50A	-	-	1.2	V	
反向恢复时间 Reverse recovery time	trr	VGS=0V, Is=50A , dI/dt=100A/μs (note 4)	-	44.4	-	ns	
反向恢复电荷 Reverse recovery charge	Qrr		-	34.6	-	nC	

## 热特性 THERMAL CHARACTERISTIC

项目 Parameter	符号 Symbol	最大值 Max	单位 Unit
结到管壳的热阻 Thermal Resistance, Junction to Case	R <sub>th(j-c)</sub>	0.7	°C/W
结到环境的热阻 Thermal Resistance, Junction to Ambient	R <sub>th(j-A)</sub>	62.5	°C/W

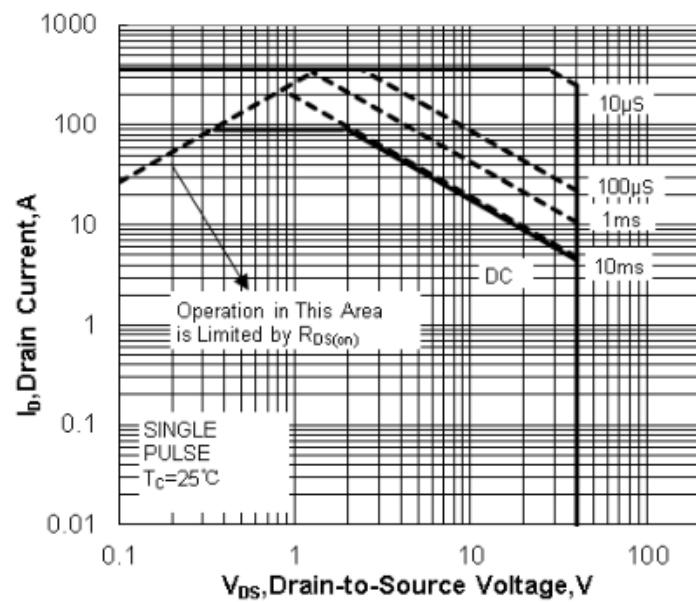
注释:

- 1: 脉冲宽度由最高结温限制
- 2: L=1mH, I<sub>AS</sub>=21A, V<sub>DD</sub>=25V, R<sub>G</sub>=25 Ω, 起始结温 T<sub>J</sub>=25°C
- 3: I<sub>SD</sub> ≤ 150A, di/dt ≤ 300A/μs, V<sub>DD</sub>≤BV<sub>DSS</sub>, 起始结温 T<sub>J</sub>=25°C
- 4: 脉冲测试: 脉冲宽度 ≤300μs, 占空比≤2%
- 5: 基本与工作温度无关

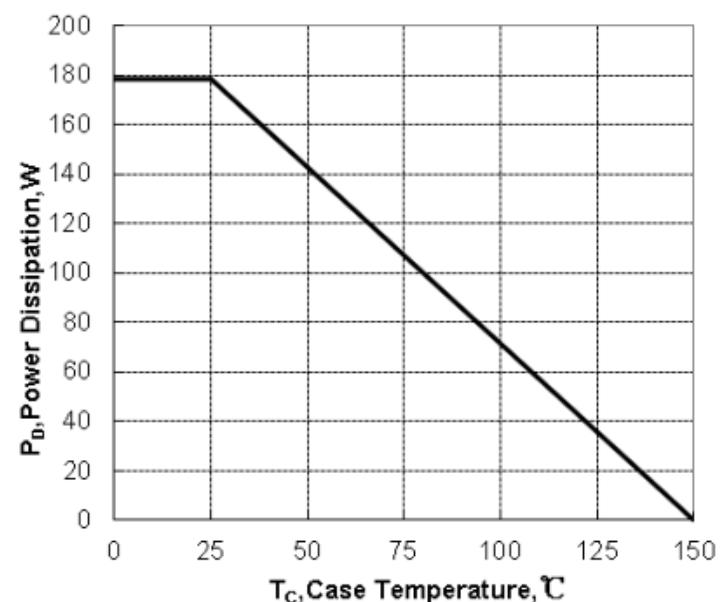
Notes:

- 1: Pulse width limited by maximum junction temperature
- 2: L=1mH, I<sub>AS</sub>=21A, V<sub>DD</sub>=25V, R<sub>G</sub>=25 Ω, Starting T<sub>J</sub>=25°C
- 3: I<sub>SD</sub> ≤ 150A, di/dt ≤ 300A/μs, V<sub>DD</sub>≤BV<sub>DSS</sub>, Starting T<sub>J</sub>=25°C
- 4: Pulse Test: Pulse Width ≤300μs, Duty Cycle≤2%
- 5: Essentially independent of operating temperature

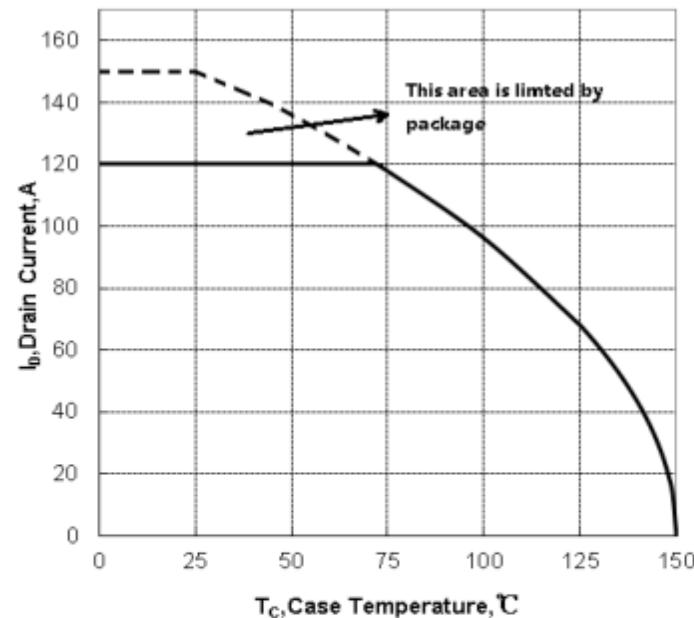
## Typical Performance Characteristics



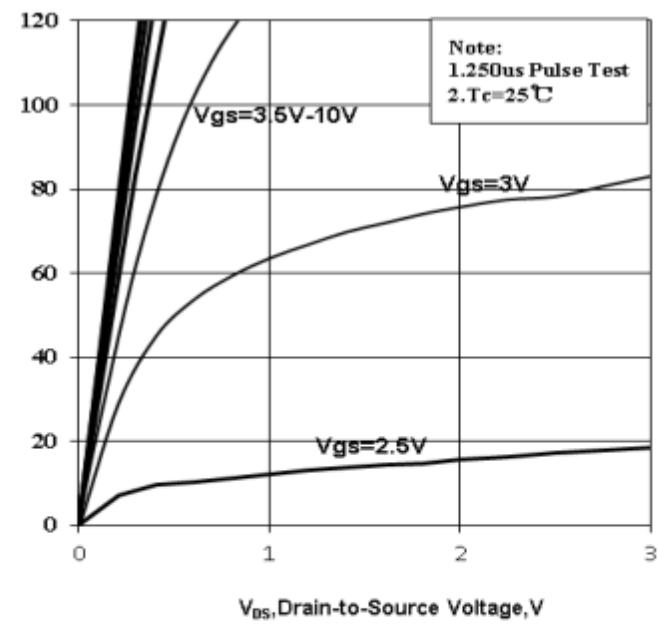
**Figure 1 . Maximum Safe Operating Area**



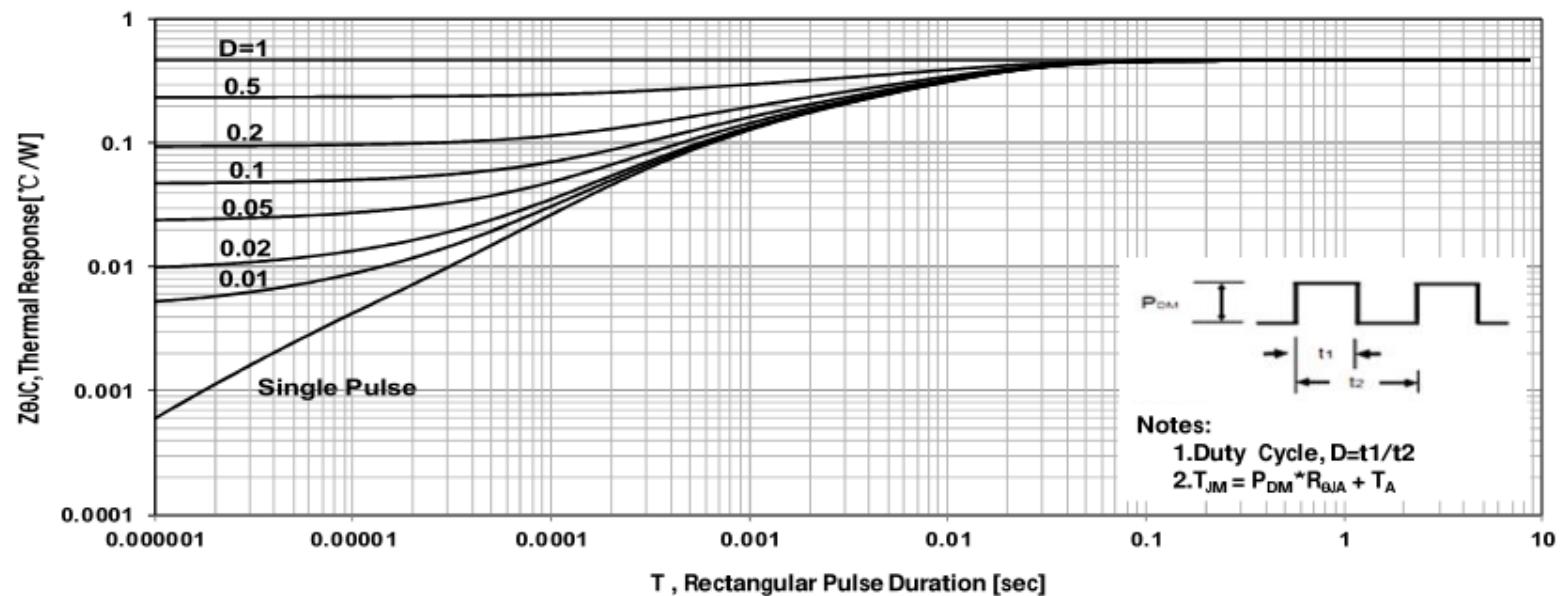
**Figure 2. Maximum Power Dissipation vs Case Temperature**



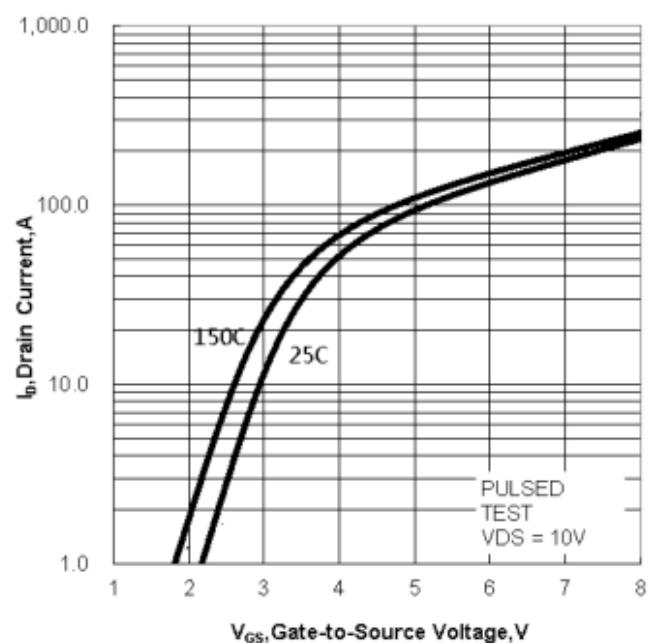
**Figure3. Maximum Continuous Drain Current vs Case Temperature**



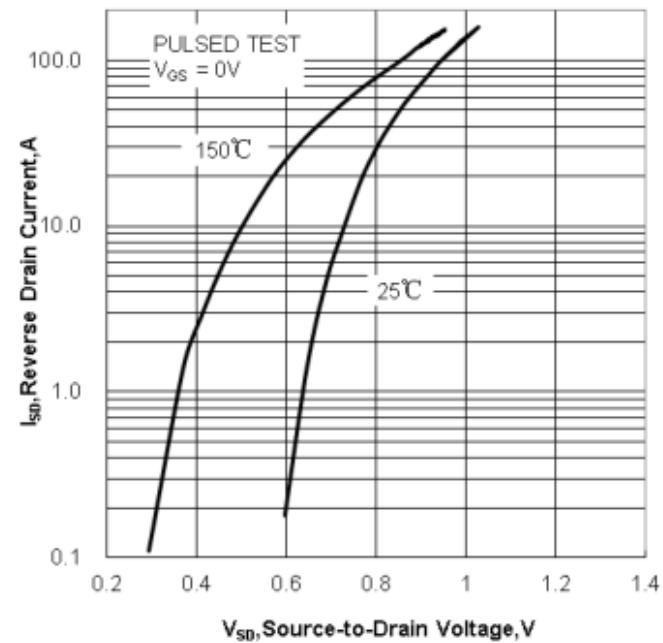
**Figure 4. Typical Output Characteristics**



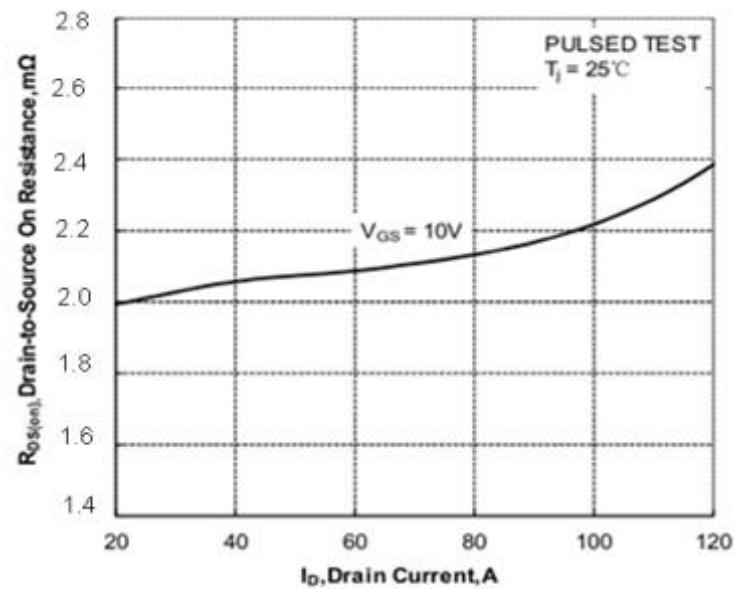
**Figure 5 Maximum Effective Thermal Impedance , Junction to Case**



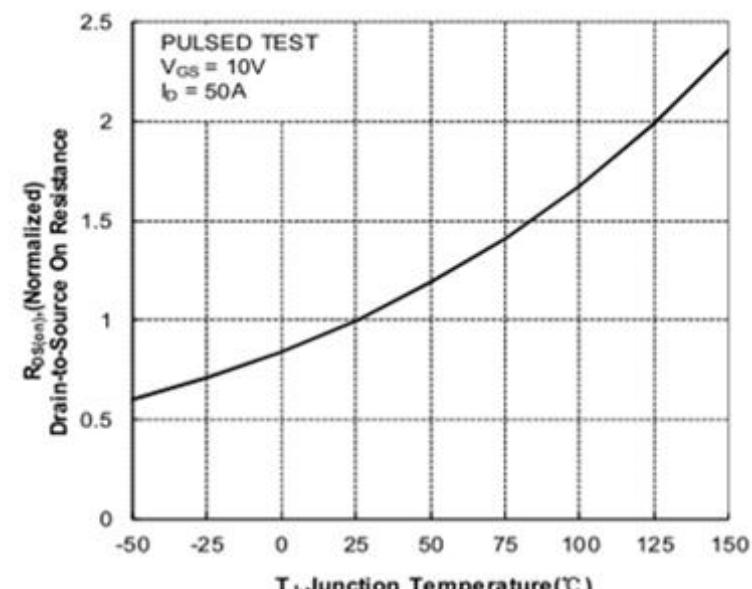
**Figure 6. Typical Transfer Characteristics**



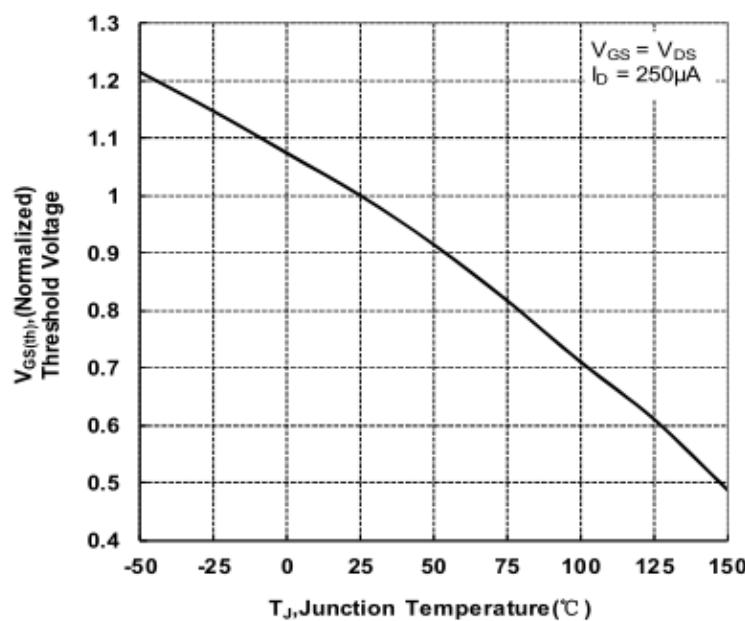
**Figure 7. Typical Body Diode Transfer Characteristics**



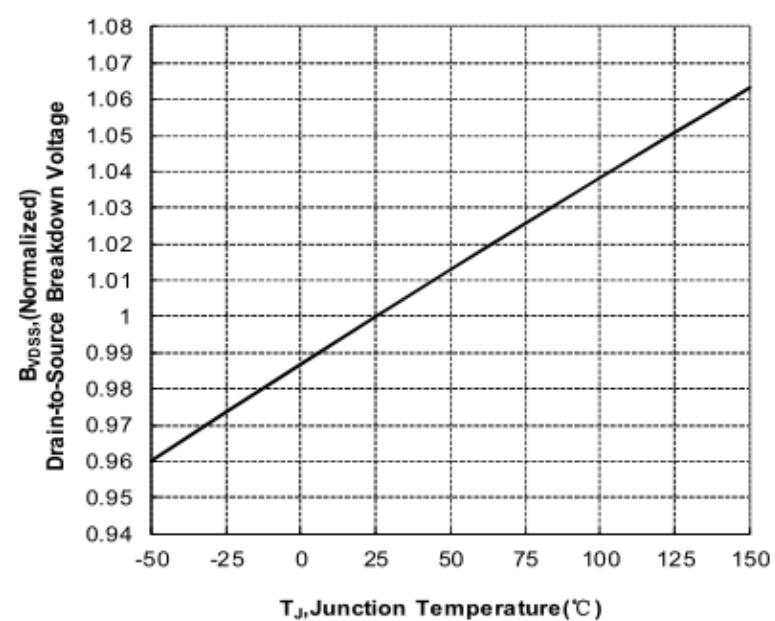
**Figure 8. Drain-to-Source On Resistance vs Drain Current**



**Figure 9. Normalized On Resistance vs Junction Temperature**



**Figure 10. Normalized Threshold Voltage vs Junction Temperature**



**Figure 11. Normalized Breakdown Voltage vs Junction Temperature**

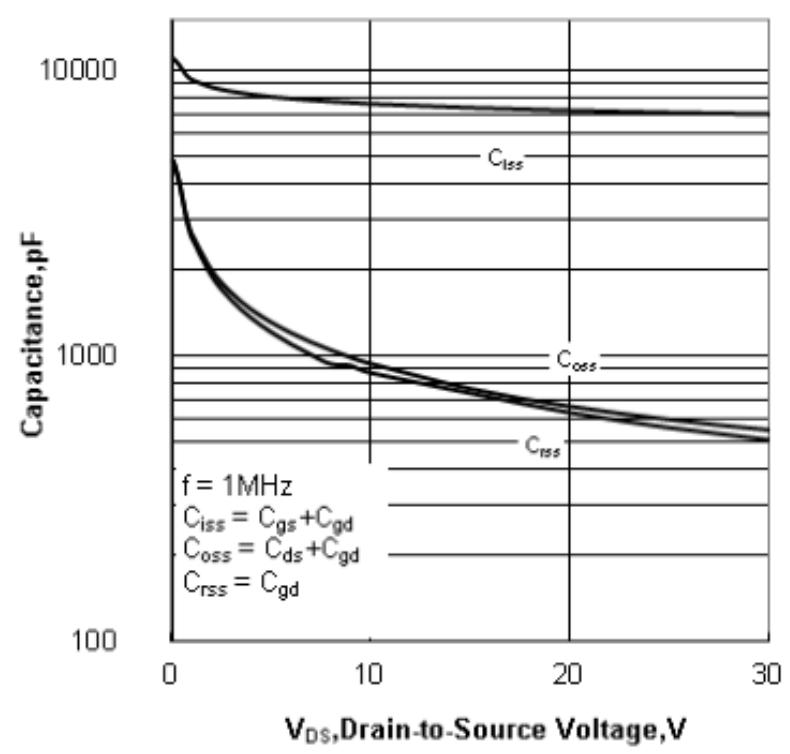


Figure 12. Capacitance Characteristics

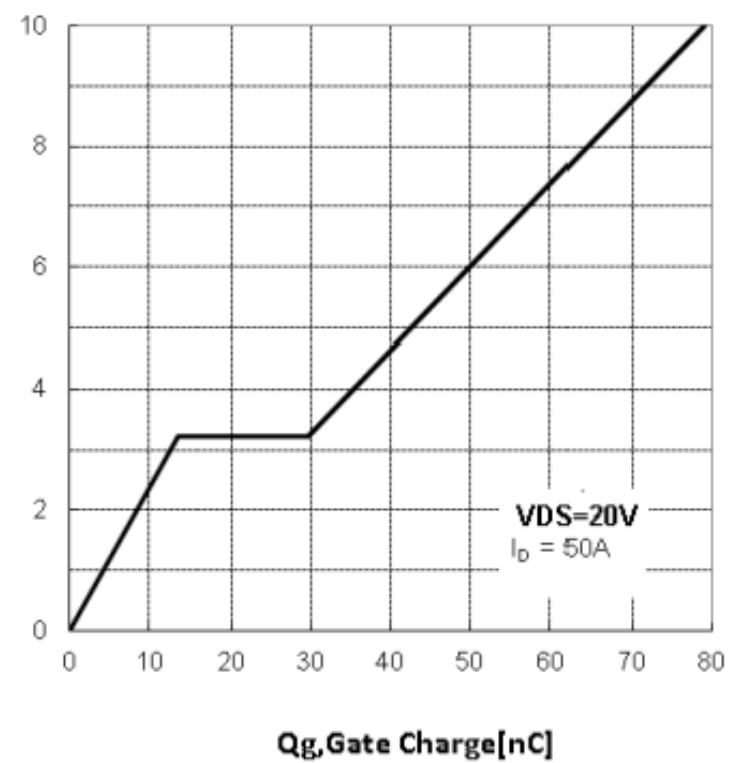
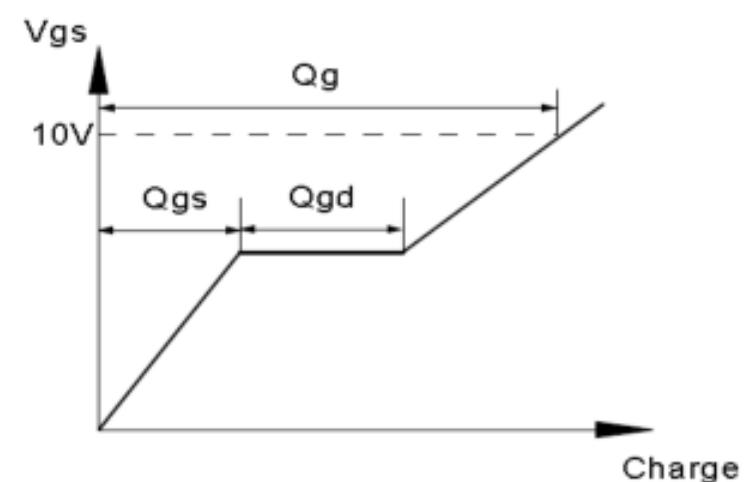
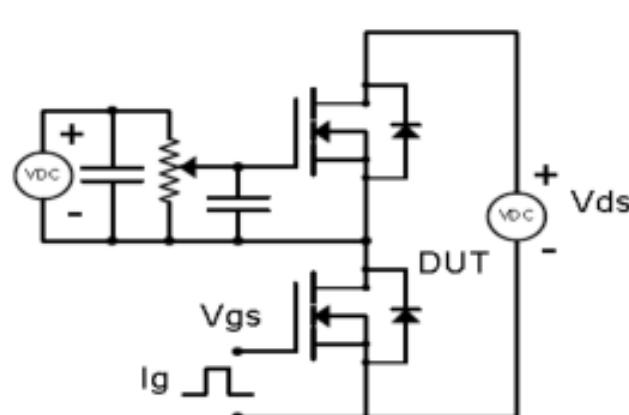


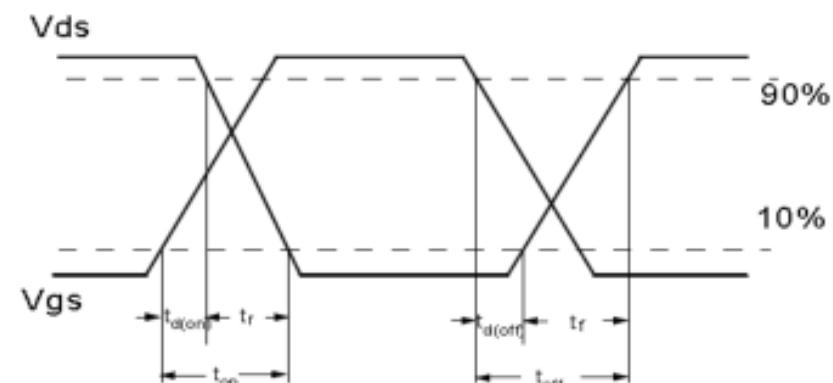
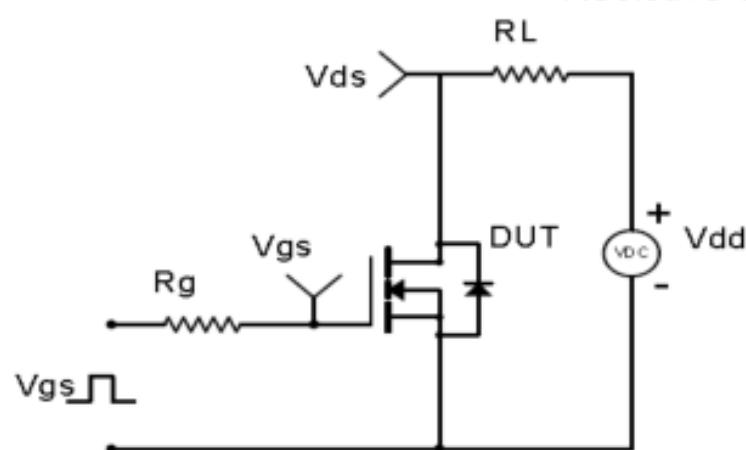
Figure 13 Typical Gate Charge vs Gate to Source Voltage

## Test Circuit & Waveform

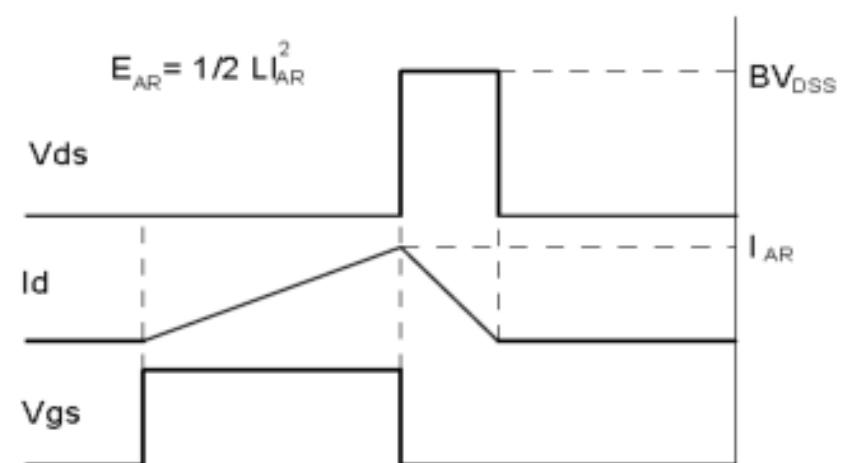
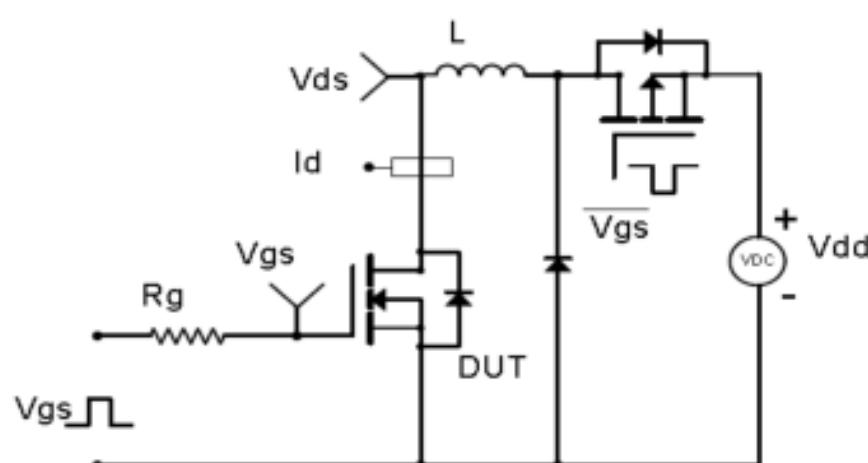
Gate Charge Test Circuit & Waveform



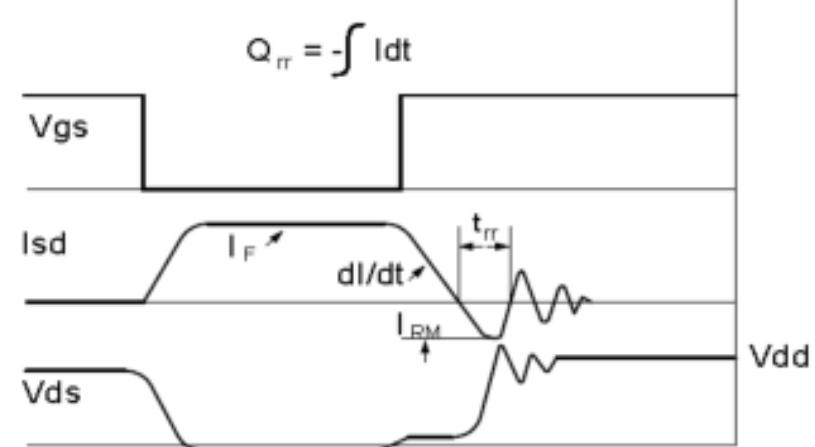
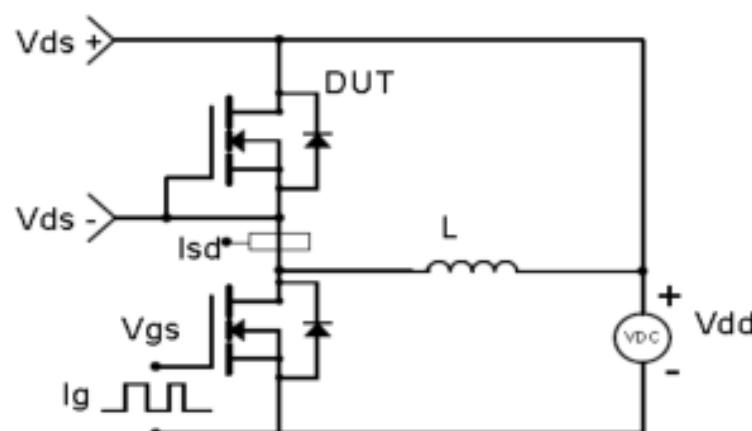
Resistive Switching Test Circuit & Waveforms



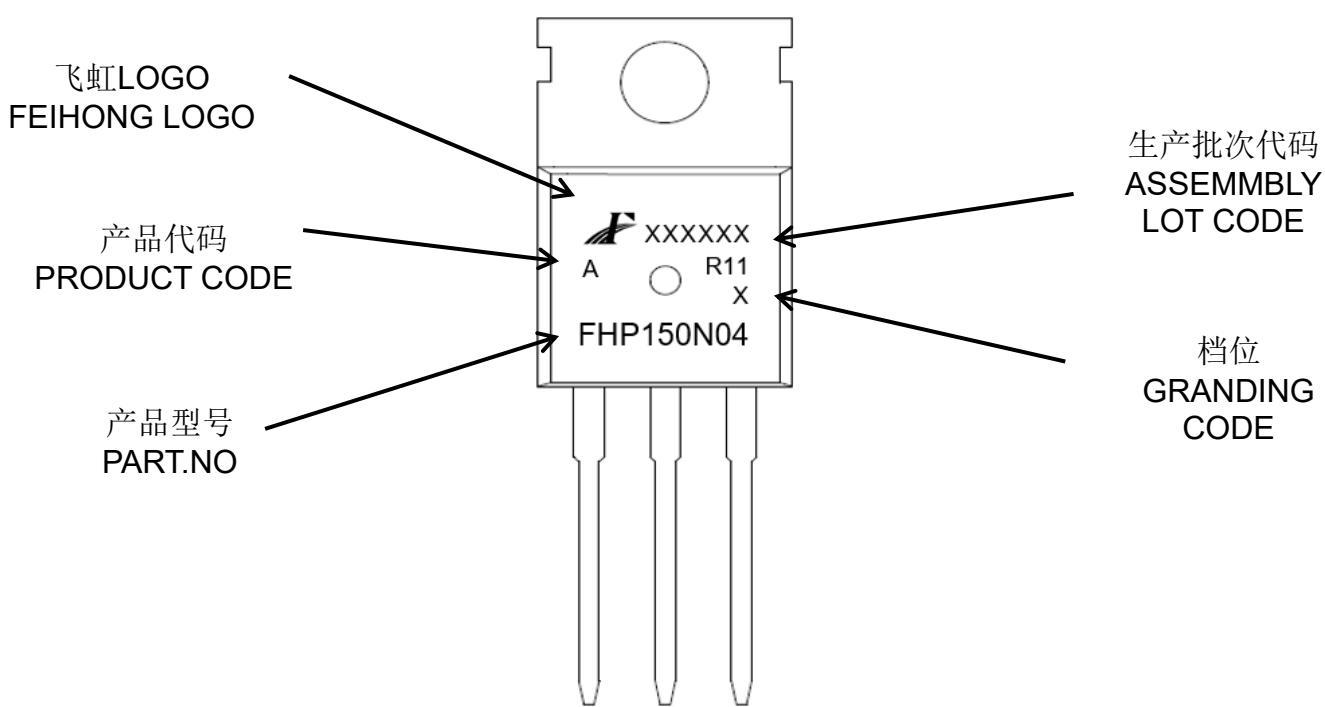
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



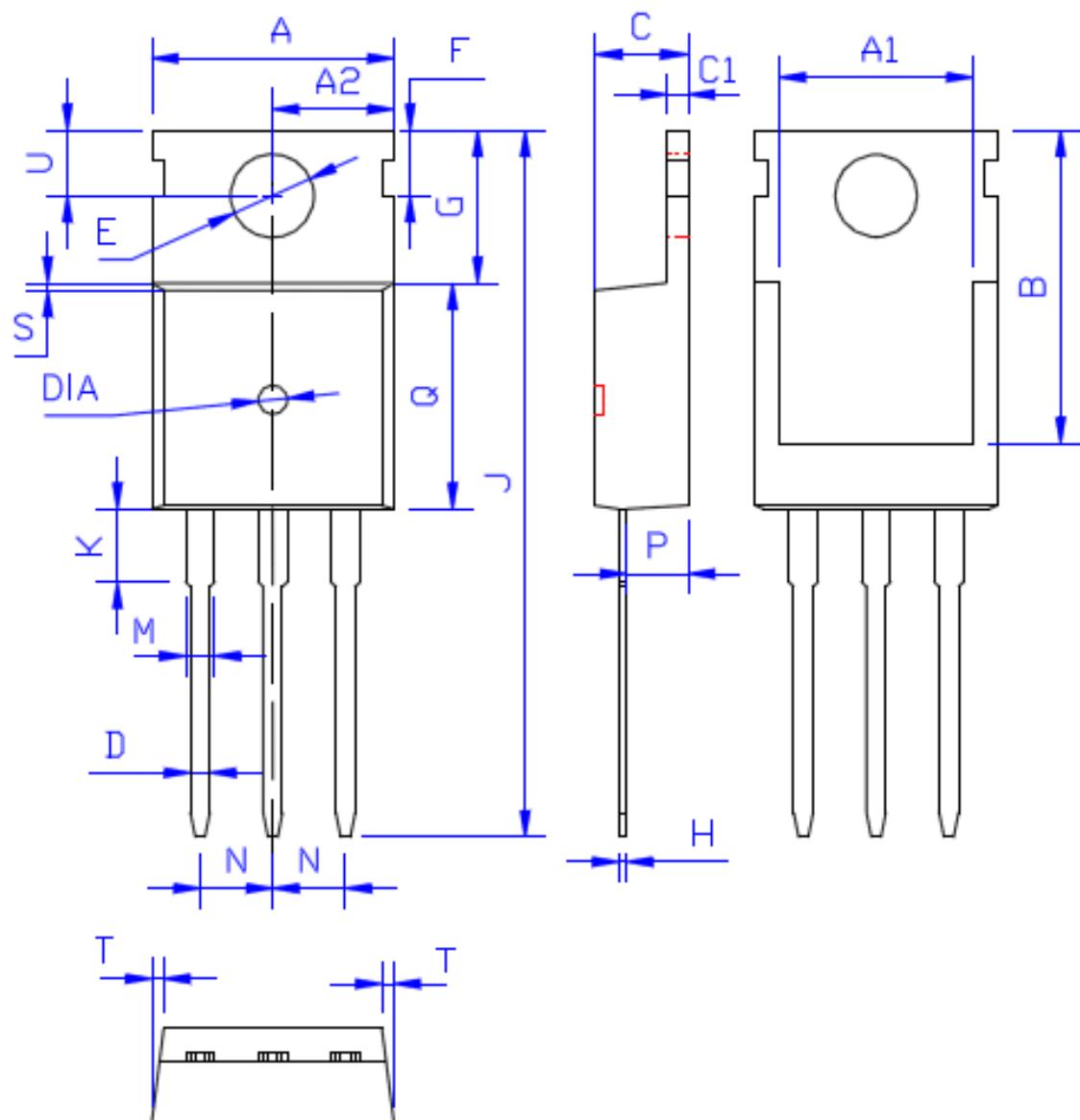
**印记 Marking:**



外形尺寸:

Package Dimension:

TO-220



DIM	MILLIMETERS
A	10.00±0.30
A1	8.00±0.30
A2	5.00±0.30
B	13.20±0.40
C	4.50±0.20
C1	1.30±0.20
D	0.80±0.20
E	3.60±0.20
F	3.00±0.30
G	6.60±0.40
H	0.50±0.20
J	28.88±0.50
K	3.00±0.30
M	1.30±0.30
N	Typical 2.54
P	2.40±0.40
Q	9.20±0.40
S	0.25±0.15
T	0.25±0.15
U	2.80±0.30
DIA	宽 1.50±0.10 深 0.50 MAX

(Unit: mm)